

Amendments to the Claims:

1-14. (Cancelled)

15. (Currently Amended) A method for testing memory, said method comprising:
testing functional memory;
repairing the functional memory by adding access to redundant elements;
re-testing the functional memory which has been repaired;
adding access to additional redundant memory which is not required for the repair; and
after ~~testing~~ re-testing the functional memory and ~~repairing the memory,~~ testing the
memory including the adding access to the additional redundant memory which has been added
which was not required for the repair, testing the additional redundant memory which has been
added which was not required for the repair.

16. (Previously Presented) A method as recited in claim 15, further comprising using repair information to repair the memory.

17. (Previously Presented) A method as recited in claim 15, wherein the step of adding access to additional redundant memory which is not required for the repair comprises forcing usage of redundant elements which are not needed to be used for repairing the memory.

18. (Previously Presented) A method as recited in claim 15, wherein the step of adding access to additional redundant memory which is not required for the repair comprises faking defects to remap good elements with redundant elements.

19. (Previously Presented) A method as recited in claim 15, further comprising checking interaction between redundant elements of the memory which are not used and adjacent functional memory.

20. (Previously Presented) A method as recited in claim 15, further comprising forcing usage of all redundant elements, and determining whether a detected failure is associated with redundant elements.

21. (Currently Amended) A mode for testing memory, said mode comprising:
means for testing functional memory;
repairing the functional memory by adding access to redundant elements;
means for re-testing the functional memory which has been repaired;
means for adding access to additional redundant memory which is not required for the repair; and

means for, after ~~testing~~ re-testing the functional memory and ~~repairing the memory;~~
~~testing the memory including the~~ adding access to the additional redundant memory which has

been added which was not required for the repair, testing the additional redundant memory which has been added which was not required for the repair.

22. (Previously Presented) A mode as recited in claim 21, further comprising means for using repair information to repair the memory.

23. (Previously Presented) A mode as recited in claim 21, further comprising means for forcing usage of redundant elements which are not needed to be used for repairing the memory.

24. (Previously Presented) A mode as recited in claim 21, further comprising means for faking defects to remap good elements with redundant elements.

25. (Previously Presented) A mode as recited in claim 21, further comprising means for checking interaction between redundant elements of the memory which are not used and adjacent functional memory.

26. (Previously Presented) A mode as recited in claim 21, further comprising means for forcing usage of all redundant elements, and determining whether a detected failure is associated with redundant elements.